ON Semiconductor[®]



Test Procedure for the LV56351HAGEVB Evaluation Board

The following steps detail the basic test procedure for all these boards:

Suggested equipment:

• Current limited DC Power Supply (e.g. ADVANTEST R6243 DC Voltage Current Source/Monitor) ···· 2	2pcs
• Digital Multimeter (e.g. ADVANTEST R6452 Digital Multimeter)	2pcs
• Multifunction Generator (e.g. NF WF1974) 1	1pc
• Electronic Load (e.g. FUJITSU ACCESS LIMITED Electric Load EUL-150αXL) ······	1pc
• Oscilloscope (e.g. LeCroy WaveRunner) ·····	1pc

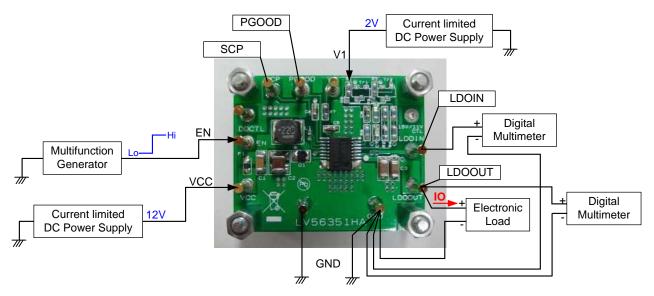


Figure 1: Test Setup

Test Procedure:

- (1) Connect the test setup as shown in Figure 1
- (2) Apply 12Vdc to VCC.
- (3) Apply 2Vdc to V1.
- (4) Apply Low level (0V) signal to EN.
- (5) Check that LDOIN=0[V] and LDOOUT=0[V].
- (6) Apply IO(load)=0[A] to LDOOUT.
- (7) Apply High level (2V) signal to EN.
- (8) Check that LDOIN=17.5[V] and LDOOUT=16.5[V]
- (9) Set IO to desired level, 0[mA] 300[mA], and measure LDOOUT voltage and LDOIN voltage.
- (10) Apply Low level signal to EN.
- (11) Turn off IO(load).
- (12) Turn off VCC, V1, and EN.